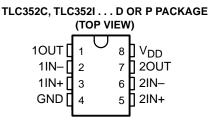
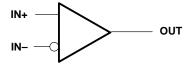
SLCS016A - SEPTEMBER 1985 - REVISED SEPTEMBER 2002

- Single- or Dual-Supply Operation
- Wide Range of Supply Voltages 1.5 V to 18 V
- **Very Low Supply Current Drain** 150 μA Typ at 5 V **65 μA Typ at 1.4 V**
- **Built-In ESD Protection**
- High Input Impedance . . . $10^{12} \Omega$ Typ
- **Extremely Low Input Bias Current 5 pA Typ**
- **Ultrastable Low Input Offset Voltage**
- Input Offset Voltage Change at Worst-Case Input Conditions Typically 0.23 µV/ Month, Including the First 30 Days
- **Common-Mode Input Voltage Range Includes Ground**
- Outputs Compatible With TTL, MOS, and **CMOS**
- Pin-Compatible With LM393



symbol (each comparator)



description

This device is fabricated using LinCMOS™ technology and consists of two independent voltage comparators, each designed to operate from a single power supply. Operation from dual supplies is also possible if the difference between the two supplies is 1.4 V to 18 V. Each device features extremely high input impedance (typically greater than $10^{12} \Omega$), which allows direct interface to high-impedance sources. The output are n-channel open-drain configurations and can be connected to achieve positive-logic wired-AND relationships. The capability of the TLC352 to operate from 1.4-V supply makes this device ideal for low-voltage battery applications.

The TLC352 has internal electrostatic discharge (ESD) protection circuits and has been classified with a 2000-V ESD rating tested under MIL-STD-883C, Method 3015. However, care should be exercised in handling this device as exposure to ESD may result in degradation of the device parametric performance.

The TLC352C is characterized for operation from 0°C to 70°C. The TLC352I is characterized for operation over the industrial temperature range of – 40°C to 85°C.

AVAILABLE OPTIONS

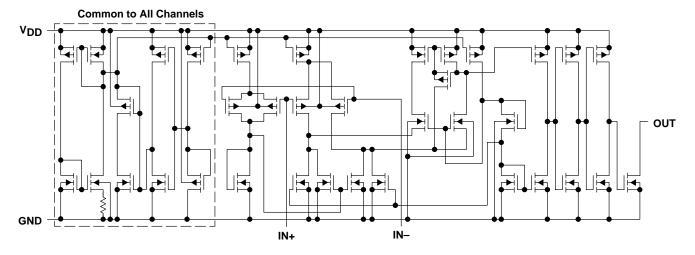
	Via may	PACKAGE					
TA	V _{IO} max AT 25°C	SMALL-OUTLINE (D)	PLASTIC DIP (P)				
0°C to 70°C	5 mV	TLC352CD	TLC352CP				
– 40°C to 85°C	5 mV	TLC352ID	TLC352IP				

The D packages are available taped and reeled. Add R suffix to device type (e.g., TLC352 CDR).

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equivalent schematic (each comparator)



absolute maximum ratings over operating free-air temperature range (unless otherwise noted)†

Supply voltage, V _{DD} (see Note 1)	18 V
Differential input voltage, V _{ID} (see Note 2)	± 18 V
Input voltage, V _I	V _{DD}
Input voltage range, V _I	– 0.3 V to 18 V
Output voltage, VO	18 V
Input current, I _I	± 5 mA
Output current, I _O	20 mA
Duration of output short circuit to ground (see Note 3)	unlimited
Continuous total dissipation	. See Dissipation Rating Table
Operating free-air temperature range, T _A TLC352C	0°C to 70°C
TLC352I	– 40°C to 85°C
Storage temperature range	– 65°C to 150°C
Lead temperature 1,6 mm (1/16 inch) from case for 10 seconds: D or P packa	age 260°C

[†] Stresses beyond those listed under "absolute maximum ratings" may cause permanent damage to the device. These are stress ratings only, and functional operation of the device at these or any other conditions beyond those indicated under "recommended operating conditions" is not implied. Exposure to absolute-maximum-rated conditions for extended periods may affect device reliability.

- NOTES: 1. All voltage values except differential voltages are with respect to the network ground.
 - 2. Differential voltages are at IN+ with respect to IN -.
 - 3. Short circuits from outputs to $V_{\mbox{DD}}$ can cause excessive heating and eventual device destruction.

DISSIPATION RATING TABLE

PACKAGE	$T_{\mbox{\scriptsize A}} \le 25^{\circ}\mbox{\scriptsize C}$ POWER RATING	DERATING FACTOR	DERATE ABOVE T _A	T _A = 70°C POWER RATING	T _A = 85°C POWER RATING
D	500 mW	5.8 mW/°C	64°C	464 mW	377 mW
P	500 mW	N/A	N/A	500 mW	500 mW



recommended operating conditions

		TLC3	52C	TLC	352I	UNIT	
		MIN	MAX	MIN	MAX	UNII	
Supply voltage, V _{DD}		1.4	16	1.4	16	V	
Common mode input voltage. V. a	V _{DD} = 5 V	0	3.5	0	3.5	\ \	
Common-mode input voltage, V _{IC}	V _{DD} = 10 V	0	8.5	0	8.5	V	
Operating free-air temperature, T _A		0	70	- 40	85	°C	

electrical characteristics at specified free-air temperature, $V_{DD} = 1.4 \text{ V}$ (unless otherwise noted)

PARAMETER		TEST CONDITIONS		TLC352C			TLC352I			UNIT
				MIN	TYP	MAX	MIN	TYP	MAX	UNIT
Input offset voltage	V _{IC} = V _{ICR} min, See Note 4		25°C		2	5		2	5	mV
input onset voltage			Full range			6.5			7	IIIV
I _{IO} Input offset current			25°C		1			1		pА
input onset current			MAX			0.3			1	nA
Input higs current			25°C		5			5		pА
input bias current			MAX			0.6			2	nA
Common-mode input voltage range	Full range		Full range	0 to		0 to			l _v l	
			r un rungo	0.2			0.2			
Low-level output voltage			25°C		100	200		100	200	mV
Low-level output voltage			Full range			200			200	111 V
Low-level output current	$V_{ID} = -0.5 V$,	$V_{OL} = 0.3 V$	25°C	1	1.6		1	1.6		mA
Supply current (two comparators)	V:p = 0.5 V	No load	25°C		65	150		65	150	
Supply current (two comparators)	VID = 0.5 V,	NO IOAU	Full range			200			200	μΑ
	Input offset voltage Input offset current Input bias current Common-mode input voltage range Low-level output voltage	Input offset voltage $V_{IC} = V_{ICR} min,$ Input offset current Input bias current Common-mode input voltage range $Low-level output voltage$ $Low-level output current$ $V_{ID} = -0.5 V,$	Input offset voltage VIC = VICR min, See Note 4 Input offset current Input bias current Common-mode input voltage range Low-level output voltage Low-level output current VID = - 0.5 V, VOL = 0.3 V	Input offset voltage $V_{IC} = V_{ICR} \text{min}, \text{See Note 4} \\ & 25^{\circ}\text{C} \\ & \text{Full range} \\ & 25^{\circ}\text{C} \\ & \text{MAX} \\ & \text{Input bias current} \\ & \\ & \text{Low-level output voltage range} \\ & \\ & \text{Low-level output current} \\ & \\ & V_{ID} = -0.5 \text{V}, V_{OL} = 0.3 \text{V} \\ & \text{Supply current (two comparators)} \\ & \\ & \\ & \text{Vip} = 0.5 \text{V}, \text{No load} \\ & \\ & \\ & \\ & \text{Supply current (two comparators)} \\ & \\ & \\ & \\ & \\ & \text{Supply current (two comparators)} \\ & \\ & \\ & \\ & \\ & \\ & \\ & \\ & \\ & \\ $	Input offset voltage	Input offset voltage	Test conditions Tat Min Typ MAX	TEST CONDITIONS TAT MIN TYP MAX MIN Input offset voltage $V_{IC} = V_{ICR} min$, $V_{ICR} min$,	Tat Min Typ Max Min Min Typ Max Min Min	TAT MIN TYP MAX MIN TYP MAX Input offset voltage $V_{IC} = V_{ICR}$ min, offset current See Note 4 25°C 2 5 2 5 Input offset current 25°C 1 1 1 1 Input bias current MAX 25°C 5 0.3 1 1 Common-mode input voltage range Full range 0 to 0.2 0.6 2 2 Low-level output voltage Full range 25°C 100 200 100 200 Low-level output current VID = -0.5 V, VOL = 0.3 V 25°C 1 1.6 1 1.6 Supply current (two comparators) VID = 0.5 V, No load No load 25°C 65 150 65 150

[†] All characteristics are measured with zero common-mode input voltage unless otherwise noted. Full range is 0°C to 70°C for TLC352C, – 40°C to 85°C for TLC352I. IMPORTANT: See Parameter Measurement Information.

TLC352
LINCMOSTM DUAL DIFFERENTIAL COMPARATOR
SLCS016A – SEPTEMBER 1985 – REVISED SEPTEMBER 2002

NOTE 4: The offset voltage limits given are the maximum values required to drive the output above 1.25 V or below 150 mV with a 10-kΩ resistor between the output and V_{DD}. They can be verified by applying the limit value to the input and checking for the appropriate output state.

electrical characteristics at specified free-air temperature, V_{DD} = 5 V (unless otherwise noted)

PARAMETER		TEST CONDITIONS		T. T	TLC352C		TLC352I			UNIT	
				TA [†]	MIN	TYP	MAX	MIN	TYP	MAX	ONT
\/10	Input offset voltage	V _{IC} = V _{ICR} min, See Note 5		25°C		1	5		1	5	mV
VIO	input onset voltage			Full range			6.5			7	IIIV
110	Input offset current			25°C		1			1		pА
lio	input onset current			MAX			0.3			1	nA
lin	Input bias current					5			5		pА
ΙΒ	input bias current						0.6			2	nA
				25°C	0 to V _{DD} – 1			0 to V _{DD} – 1			
VICR	Common-mode input voltage range			Full range	0 to V _{DD} – 1.5			0 to V _{DD} – 1.5			V
lau	High level output ourrent	V:= - 1 V	V _{OH} = 5 V	25°C		0.1			0.1		nA
ЮН	High-level output current	V _{ID} = 1 V	V _{OH} = 15 V	Full range			1			1	μΑ
\/a:	Low level output voltage	V:= - 1 V	le: - 4 m A	25°C		150	400		150	400	mV
VOL	Low-level output voltage	$V_{ID} = 1 V$	$I_{OL} = 4 \text{ mA}$	Full range			700			700	1117
lOL	Low-level output current	$V_{1D} = -1 V$,	V _{OL} = 1.5 V	25°C	6	16		6	16		mA
Inn	Supply current	V:n = 1 V	No load	25°C		0.15	0.3		0.15	0.3	mA
IDD	(two comparators)	V _{ID} = 1 V, No load	INU IUAU	Full range			0.4			0.4	IIIA

[†] All characteristics are measured with zero common-mode input voltage unless otherwise noted. Full range is 0°C to 70°C for TLC352C, - 40°C to 85°C for TLC352I. IMPORTANT: See Parameter Measurement Information.

NOTE 5: The offset voltage limits given are the maximum values required to drive the output above 4 V or below 400 mV with a 10-kΩ resistor between the output and V_{DD}. They can be verified by applying the limit value to the input and checking for the appropriate output state.

switching characteristics, V_{DD} = 5 V, T_A = 25°C

PARAMETER	TEST CONDITIONS					TLC352C, TLC352I		
PARAMETER TEST CONDITIONS MIN					TYP	MAX	UNIT	
Response time	R _L connected to 5 V through 5	.1 kΩ,,	100-mV input step with 5-mV overdrive		650			
	$C_L = 15 \text{ pF}^{\ddagger}$,	See Note 6	TTL-level input step		200		ns	

‡C_L includes probe and jig capacitance.

NOTE 6: The response time specified is the interval between the input step function and the instant when the output crosses 1.4 V.

PARAMETER MEASUREMENT INFORMATION

The digital output stage of the TLC352 can be damaged if it is held in the linear region of the transfer curve. Conventional operational amplifier/comparator testing incorporates the use of a servo loop that is designed to force the device output to a level within this linear region. Since the servo-loop method of testing cannot be used, the following alternative for measuring parameters such as input offset voltage, common-mode rejection, etc., are offered.

To verify that the input offset voltage falls within the limits specified, the limit value is applied to the input as shown in Figure 1(a). With the noninverting input positive with respect to the inverting input, the output should be high. With the input polarity reversed, the output should be low.

A similar test can be made to verify the input offset voltage at the common-mode extremes. The supply voltages can be slewed as shown in Figure 1(b) for the V_{ICR} test, rather than changing the input voltages, to provide greater accuracy.

A close approximation of the input offset voltage can be obtained by using a binary search method to vary the differential input voltage while monitoring the output state. When the applied input voltage differential is equal but opposite in polarity to the input offset voltage, the output changes state.

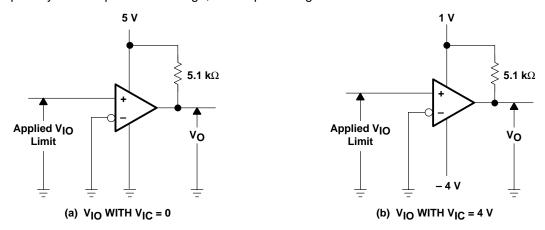


Figure 1. Method for Verifying That Input Offset Voltage Is Within Specified Limits

PARAMETER INFORMATION

Figure 2 illustrates a practical circuit for direct dc measurement of input offset voltage that does not bias the comparator into the linear region. The circuit consists of a switching-mode servo loop in which U1a generates a triangular waveform of approximately 20-mV amplitude. U1b acts as a buffer, with C2 and R4 removing any residual dc offset. The signal is then applied to the inverting input of the comparator under test, while the noninverting input is driven by the output of the integrator formed by U1c through the voltage divider formed by R9 and R10. The loop reaches a stable operating point when the output of the comparator under test has a duty cycle of exactly 50%, which can only occur when the incoming triangle wave is sliced symmetrically or when the voltage at the noninverting input exactly equals the input offset voltage.

Voltage divider R9 and R10 provides a step up of the input offset voltage by a factor of 100 to make measurement easier. The values of R5, R8, R9, and R10 can significantly influence the accuracy of the reading; therefore, it is suggested that their tolerance level be 1% or lower.

Measuring the extremely low values of input current requires isolation from all other sources of leakage current and compensation for the leakage of the test socket and board. With a good picoammeter, the socket and board leakage can be measured with no device in the socket. Subsequently, this open-socket leakage value can be subtracted from the measurement obtained with a device in the socket to obtain the actual input current of the device.

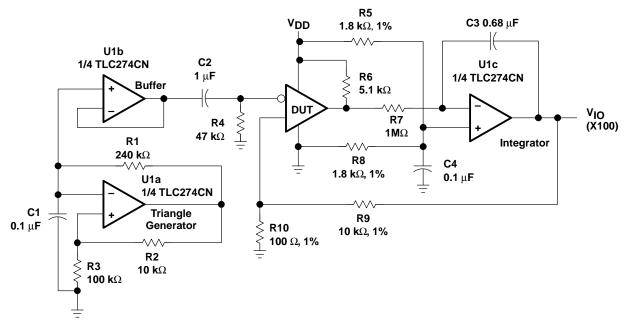
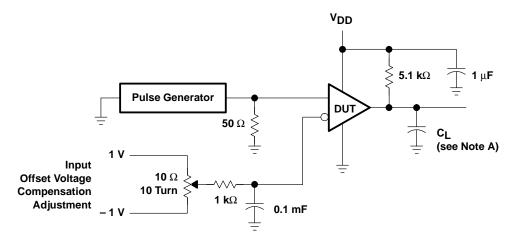


Figure 2. Circuit for Input Offset Voltage Measurement

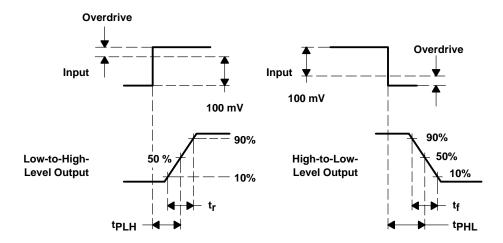


PARAMETER MEASUREMENT INFORMATION

Response time is defined as the interval between the application of an input step function and the instant when the output reaches 50% of its maximum value. Response time, low-to-high-level output, is measured from the leading edge of the input pulse, while response time, high-to-low level output, is measured from the trailing edge of the input pulse. Response-time measurement at low input signal levels can be greatly affected by the input offset voltage. The offset voltage should be balanced by the adjustment at the inverting input (as shown in Figure 3) so that the circuit is just at the transition point. Then a low signal, for example 105-mV or 5-mV overdrive, causes the output to change state.



TEST CIRCUIT



VOLTAGE WAVEFORMS

NOTE A: C_I includes probe and jig capacitance.

Figure 3. Response, Rise, and Fall Times Circuit and Voltage Waveforms

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